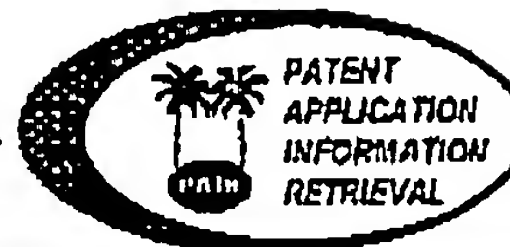




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PATENT APPLICATION INFORMATION RETRIEVAL



Search results as of: 4-1-2005:12:16:19 E.T.

Search results for application number: 10/616,147			
Application Number:	10/616,147	Customer Number:	36872
Filing or 371(c) Date:	07-08-2003	Status:	Docketed New Case - Ready for Examination
Application Type:	Utility	Status Date:	12-12-2003
Examiner Name:	STEIN, STEPHEN J	Location:	ELECTRONIC
Group Art Unit:	1775	Location Date:	-
Confirmation Number:	2078	Earliest Publication No:	US 2005-0008880 A1
Attorney Docket Number:	KOV-004	Earliest Publication Date:	01-13-2005
Class/ Sub-Class:	428/446	Patent Number:	-
First Named Inventor:	Klaus Kunze, Half Moon Bay, CA	Issue Date of Patent:	-
Title Of Invention:	Compositions and methods for forming a semiconducting and/or silicon-containing film, and structures formed therefrom		

Search Options

Assignments
Display References
Image File Wrapper
Publication Review
Published Documents

File History	
Date	Contents Description
07-07-2004	Rescind Nonpublication Request for Pre Grant Publication
04-13-2004	Correspondence Address Change
12-12-2003	Case Docketed to Examiner in GAU
12-12-2003	Reference capture on IDS
12-12-2003	Reference capture on IDS
12-12-2003	Reference capture on IDS
07-08-2003	Information Disclosure Statement (IDS) Filed
11-18-2003	Information Disclosure Statement (IDS) Filed
08-25-2003	Information Disclosure Statement (IDS) Filed
10-06-2003	Application Return from OIPE
10-06-2003	Application Return TO OIPE
10-03-2003	Application Return from OIPE

10-06-2003	Application Is Now Complete
10-06-2003	Pre-Exam Office Action Withdrawn
10-03-2003	Application Return TO OIPE
10-03-2003	Application Dispatched from OIPE
10-06-2003	Application Is Now Complete
07-08-2003	PGPub nonPub Request
09-22-2003	Cleared by L&R (LARS)
09-22-2003	Referred to Level 2 (LARS) by OIPE CSR
09-02-2003	IFW Scan & PACR Auto Security Review
07-08-2003	Initial Exam Team nn